

JEDEC STANDARD

Measurement and Reporting of Alpha Particle and Terrestrial Cosmic Ray-Induced Soft Errors in Semiconductor Devices

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RAY INDUCED SOFT ERRORS IN SEMICONDUCTOR DEVICES**

CONTENTS

	Page
Foreword	iii
Introduction.....	iii
1 Scope	1
2 Terms and definitions	3
3 Test equipment and software requirements	8
3.1 Test plan.....	8
3.2 Test equipment.....	11
3.3 Test conditions	12
3.4 Considerations for Soft Error Testing of Individual Circuit Elements	15
3.5 Considerations for IC Testing.....	16
4 Real-time (unaccelerated and high-altitude) soft error test procedures	21
4.1 Background.....	21
4.2 Test facilities and equipment	21
4.3 Testing procedures.....	21
4.4 Differences in real-time soft error tests and actual end-user observed fail rates	26
5 Accelerated alpha particle test procedure	27
5.1 Background.....	27
5.2 Alpha particle environment.....	28
5.3 Packaging for alpha particle testing.....	28
5.4 Alpha particle sources.....	29
5.5 Test procedure and results.....	32
5.6 Interferences.....	35
6 Accelerated high-energy neutron test procedures.....	36
6.1 Background.....	36
6.2 Test facilities.....	37
6.3 Angular Dependence Considerations.....	37
6.4 Beam parameters.....	37
6.5 Fundamental quantities: soft error cross-section and soft error rate	39
6.6 Interferences - Scattering, secondary ion effects and thermal neutrons at the DUT.....	48